

**FORM PTO-1449** U.S. Department of Commerce  
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ATTY. DOCKET NO.

**500.34397CV2**

SERIAL NO.  
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08/610,488

### INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

APPLICANT  
**MIURA, et al.**

**FILING DATE**  
**October 16, 2001**

GROUP (of parent)  
2813

100-44971 U.S. PTO

9/09/977207

10/16/01

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
T.J		5	2	9	0	7	1	8	3-94	Fearon, et al.	—	—	
		5	0	4	5	4	9	2	9-91	Huie, et al.	—	—	
		5	6	3	7	5	2	8	6/97	Higashitani et al	—	—	
		5	2	1	0	0	5	6	5/93	Pong et al	—	—	
		5	1	5	1	3	8	1	9/92	Liu et al	—	—	
		5	1	3	2	2	4	4	7/92	Roy	—	—	
T.J		3	8	5	3	6	3	3	12/74	Armstrong	—	—	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
TJ		0	2	1	4	4	2	1	3-87	Europe	—	—		
	5	7	2	0	7	3	6	6	12-82	Japan	—	—	abstract	
	5	8	0	3	9	0	1	4	3-83	Japan	—	—	abstract	
	6	2	0	9	4	9	2	6	5-87	Japan	—	—		
	0	3	2	5	7	8	2	8	1991	Japan	—	—	abstract	
	0	5	2	6	7	3	3	3	1993	Japan	—	—	abstract	
	0	4	3	1	6	3	3	2	1992	Japan	—	—	abstract	
TJ		A	3	1	1	7	3	3	1989	Japan	—	—	abstract	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

T.D		Patent Abstract of Japan - Publication No. 01255228 - Publication Date October 1989
T.D		Patrice Deroux-Dauhphin er al.: "Physical and electrical characterization of a SILO Isolation structure", <u>IEEE Transactions On Electron Devices</u> , vol. ED-32, no. 11, November 1985, pages 2392-2398

EXAMINER T. DANK

DATE CONSIDERED 2/25/02

**EXAMINER:** Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.